



Traceability Japan TC Chapter Meeting Summary and Minutes

Thursday, December 15, 2022, 15:30 – 16:30

OVTCCM / SEMICON Japan @Tokyo Big Sight (Hybrid)

TC Chapter Announcements

Next TC Chapter Meeting

December 14, 2023, 15:30-16:30

SEMICON Japan @Tokyo Big Sight + OVTCCM (Hybrid)

*Tentative

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chairs: *Yoichi Iga (Self)*, Hirokazu Tsunobuchi (Consultant)

SEMI Staff: Nobuko Okayasu

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
<i>Self</i>	<i>Iga</i>	<i>Yoichi</i>	<i>Tokyo Electron</i>	<i>Akimoto</i>	<i>Toshikazu</i>
Self	Tsunobuchi	Hirokazu	Swagelok Company	Matsumoto	Takashi
Global Wafers Japan	Takeda	Ryuji	AIST	Kobara	Kazunori
<i>Semitronix Corporation</i>	<i>Tan</i>	<i>Christine</i>	<i>Omron</i>	<i>Infelise</i>	<i>Nick</i>
<i>Tokyo Electron</i>	<i>Akimoto</i>	<i>Toshikazu</i>	SEMI Japan	Kanno	Hirofumi
<i>Murata Machinery</i>	<i>Tominaga</i>	<i>Tadamasa</i>	SEMI Japan	Okayasu	Nobuko

Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
None		

Table 3 Committee Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
None	

Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
6935	Reapproval of SEMI T19-0311 (Reapproved 0717): Specification for Device Marking	Passed

Note 1: **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

Note 2: **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.



Table 5 Activities Approved by the GCS prior to the Originating TC Chapter meeting

#	Type	SC/TF/WG	Details
None			

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

#	SC/TF/WG	Details
None		

Note 1: SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARE>

Table 7 Authorized Ballots

#	When	TF	Details
None			

Table 8 SNARF(s) Granted a One-Year Extension

#	TF	Title	Expiration Date
None			

Table 9 SNARF(s) Abolished

#	TF	Title
None		

Table 10 Standard(s) to receive Inactive Status

Standard Designation	Title
None	

Table 11 New Action Items

Item #	Assigned to	Details
None		

Table 12 Previous Meeting Action Items

Item #	Assigned to	Details
None		



1 Welcome, Reminders, and Introductions

Hirokazu Tsunobuchi (Consultant) called the meeting to order at 15:30. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: 01-01_Required Element Nov 2022_E+J (new template)

2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion:	To approve the minutes of the previous meeting as written.
By / 2nd:	Tadamasa Tominaga (Murata Machinery) / Ryuji Takeda (Global Wafers Japan)
Discussion:	None
Vote:	8 in favor and 0 opposed. Motion passed.

Attachment: 02-01_20220616_Traceability-Japan_MeetingMinutes_approved

3 Liaison Reports

3.1 North America TC Chapter

Nobuko Okayasu (SEMI Japan) reported for the Traceability North America TC Chapter as attached material.

Attachment: 03-01_NA Liaison Report - Traceability Oct-2022

4 Staff Report

Nobuko Okayasu (SEMI Japan) gave the SEMI Staff Report as attached material.

Attachment: 04-01_Staff Report Nov 2022 v5 (1)

5 Ballot Review

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
6935	Reapproval of SEMI T19-0311 (Reapproved 0717): Specification for Device Marking	Passed

NOTE1 : TC Chapter adjudication on ballots reviewed is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment number for each balloted document is provided under each ballot review section below.

Attachment: 05-01_6935

6 Subcommittee and Task Force Reports

Hirokazu Tsunobuchi (Consultant) reported the following TFs as attached materials.

6.1 5 Year Review Task Force



- 6.2 Japan Single Device Traceability (SDT) liaison TF
- 6.3 Japan Equipment and Materials Traceability (EMT) liaison TF
- 6.4 Panel Level Packaging (PLP) Glass Carrier ID Marking Task Force
- 6.5 Blockchain TF

Attachment: 06-01_TC Chapter Round Table (Traceability)
06-02_20221215SDTEMT_Liaison_Joint_TF_Minutes_v2

7 Old Business

7.1 5 Year Review Check

- SEMI T22-0212 (Reapproved 0618)
Specification for Traceability by Self Authentication Service Body and Authentication Service Body
- SEMI T15-0818
Specification for Jig ID: Concept

7.2 SNARF Project Period Check

None

8 New Business

None

9 Next Meeting and Adjournment

The next meeting is December 14, 2023, 15:30-16:30
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*Tentative

Having no further business, a motion was made to adjourn. Adjournment was at 16:15.

Respectfully submitted by:

Nobuko Okayasu

SEMI Japan

Phone: +81.3.3222.5863

Email: nokayasu@semi.org

Minutes tentatively approved by:

Yoichi Iga (Self), Co-chair	2022/12/21
Hirokazu Tsunobuchi (Self), Co-chair	2022/12/22

Table 13 Index of Available Attachments#1

<i>Title</i>	<i>Title</i>
01-01_Required Element Nov 2022_E+J (new template)	05-01_6935



02-01_20220616_Traceability-Japan_MeetingMinutes_approved	06-01_TC Chapter Round Table (Traceability)
03-01_NA Liaison Report - Traceablility Oct-2022	06-02_20221215SDTEMT_Liaison_Joint_TF_Minutes_v2
04-01_Staff Report Nov 2022 v5 (1)	

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Nobuko Okayasu at the contact information above.